Device Modeling Report

COMPONENTS: MOSFET (Model Parameters)
PART NUMBER: 2SK2992
MANUFACTURER: TOSHIBA
Body Diode (Model Parameters) / ESD Protection Diode

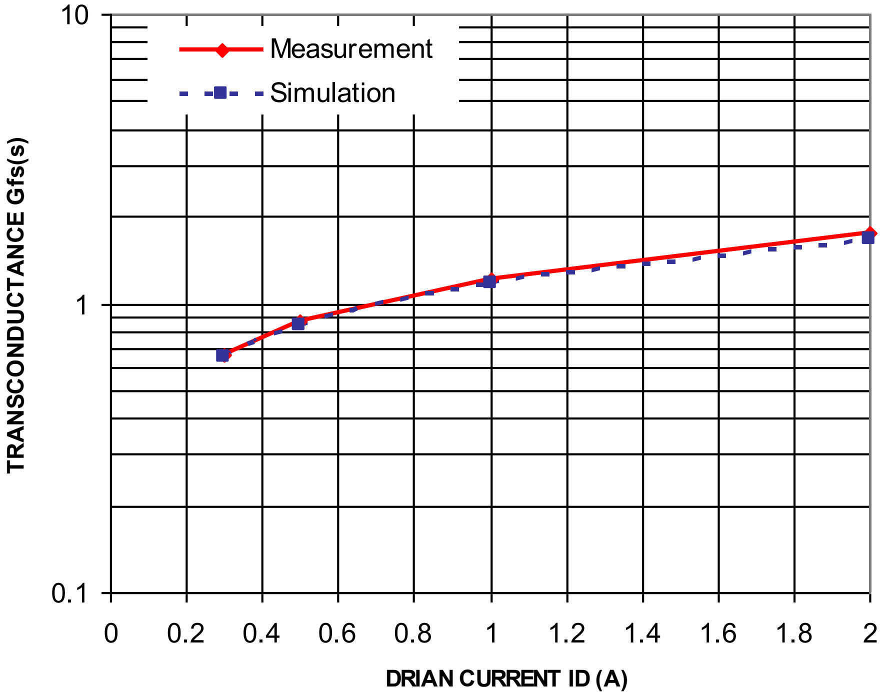
Bee Technologies Inc.

MOSFET MODEL PARAMETERS

PSpice model parameter	Model description
LEVEL	
L	Channel Length
W	Channel Width
KP	Transconductance
RS	Source Ohmic Resistance
RD	Ohmic Drain Resistance
VTO	Zero-bias Threshold Voltage
RDS	Drain-Source Shunt Resistance
TOX	Gate Oxide Thickness
CGSO	Zero-bias Gate-Source Capacitance
CGDO	Zero-bias Gate-Drain Capacitance
CBD	Zero-bias Bulk-Drain Junction Capacitance
MJ	Bulk Junction Grading Coefficient
PB	Bulk Junction Potential
FC	Bulk Junction Forward-bias Capacitance Coefficient
RG	Gate Ohmic Resistance
IS	Bulk Junction Saturation Current
N	Bulk Junction Emission Coefficient
RB	Bulk Series Resistance
PHI	Surface Inversion Potential
GAMMA	Body-effect Parameter
DELTA	Width effect on Threshold Voltage
ETA	Static Feedback on Threshold Voltage
THETA	Mobility Modulation
KAPPA	Saturation Field Factor
VMAX	Maximum Drift Velocity of Carriers
XJ	Metallurgical Junction Depth
UO	Surface Mobility

Transconductance Characteristic

Circuit Simulation Result

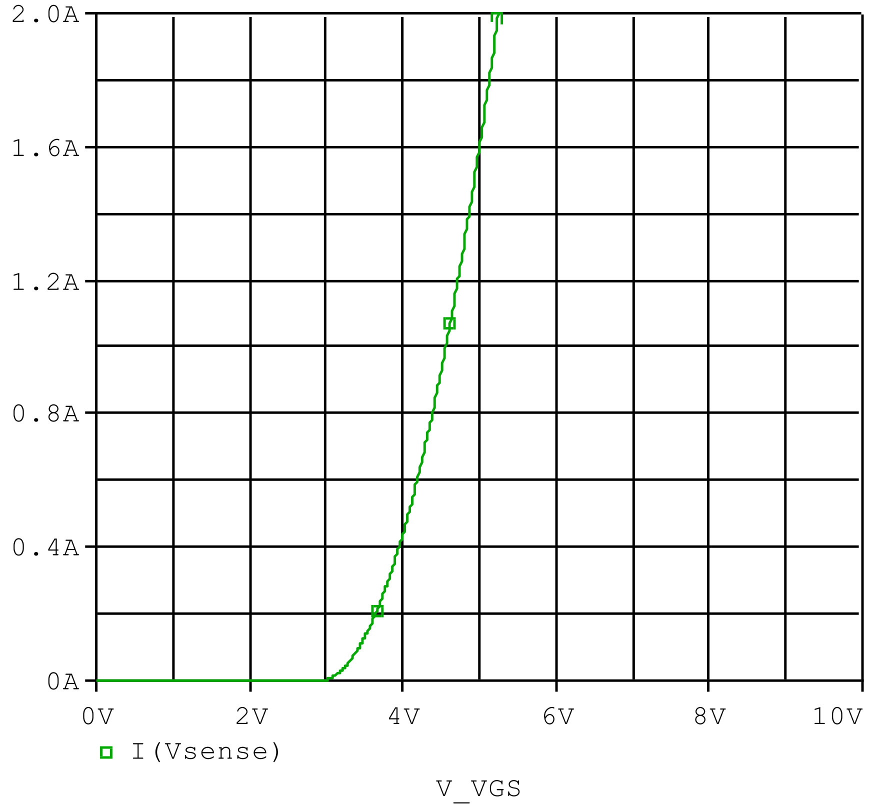


Comparison table

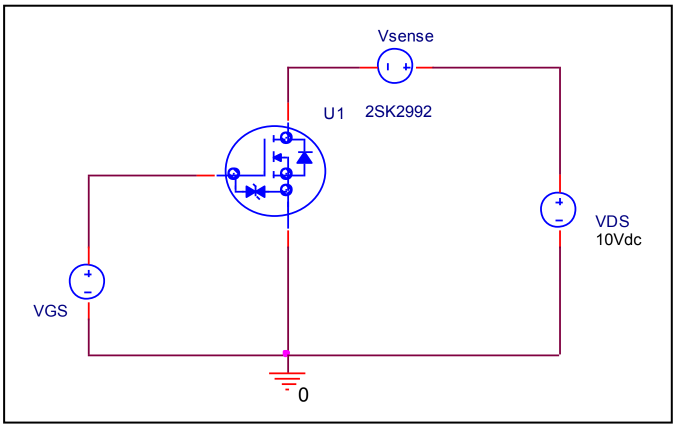
Id(A)	Gfs(S)		Error(%)
	Measurement	Simulation	
0.1	0.09704	0.09804	1.03051
0.2	0.22927	0.22727	-0.87232
0.4	0.34854	0.35054	0.57382
1.2	0.56366	0.55787	-1.02722
1.6	0.70985	0.70765	-0.30992
2	1.03093	1.04033	0.91180

Vgs-Id Characteristic

Circuit Simulation result

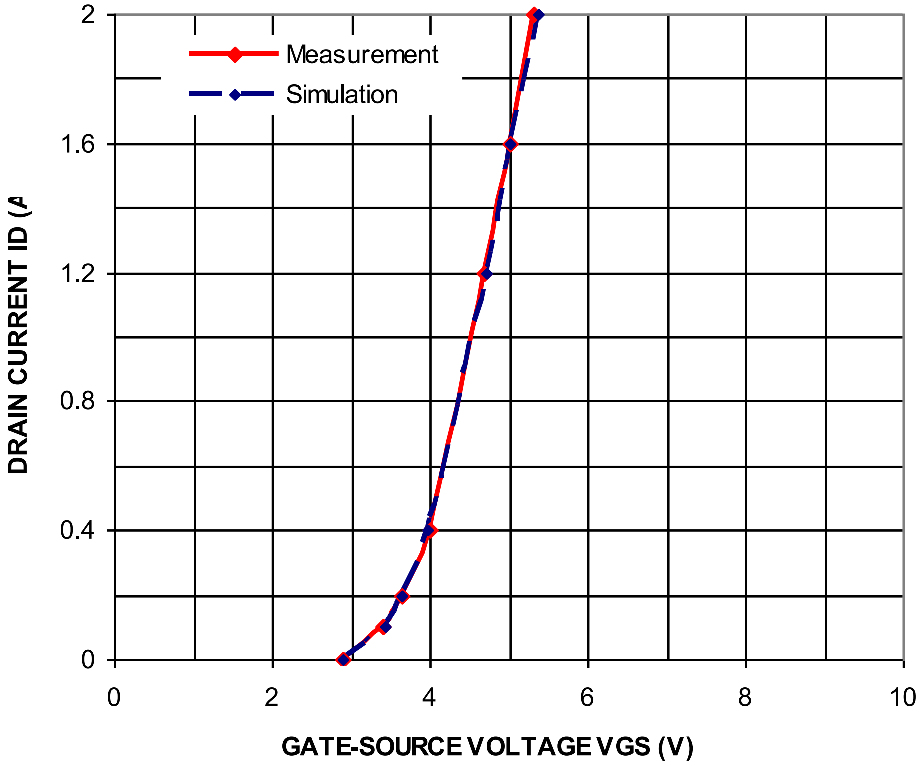


Evaluation circuit



Comparison Graph

Circuit Simulation Result

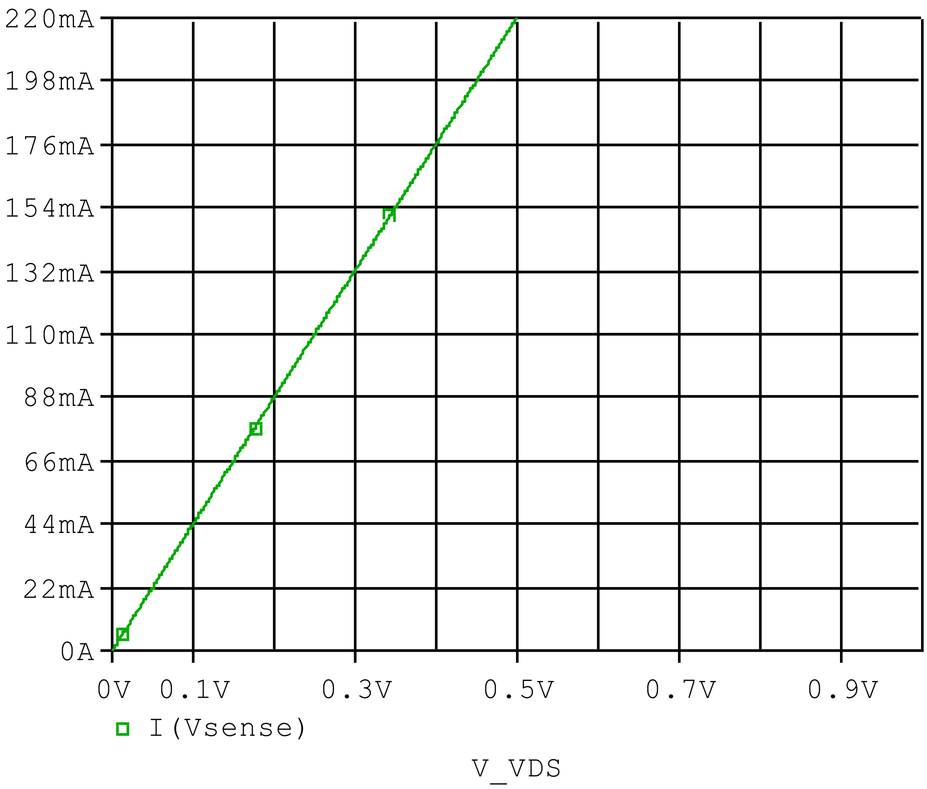


Simulation Result

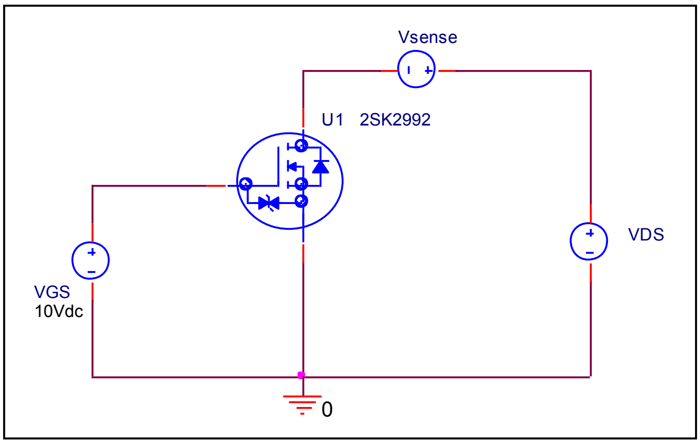
I_D(A)	V_{GS}(V)		Error (%)
	Measurement	Simulation	
0.1	3.4000	3.4298	0.8765
0.2	3.6500	3.6456	-0.1205
0.4	4.0000	3.9700	-0.7500
1.2	4.7000	4.7187	0.3979
1.6	5.0000	5.0006	0.0120
2	5.3000	5.3807	1.5217

Rds(on) Characteristic

Circuit Simulation result



Evaluation circuit

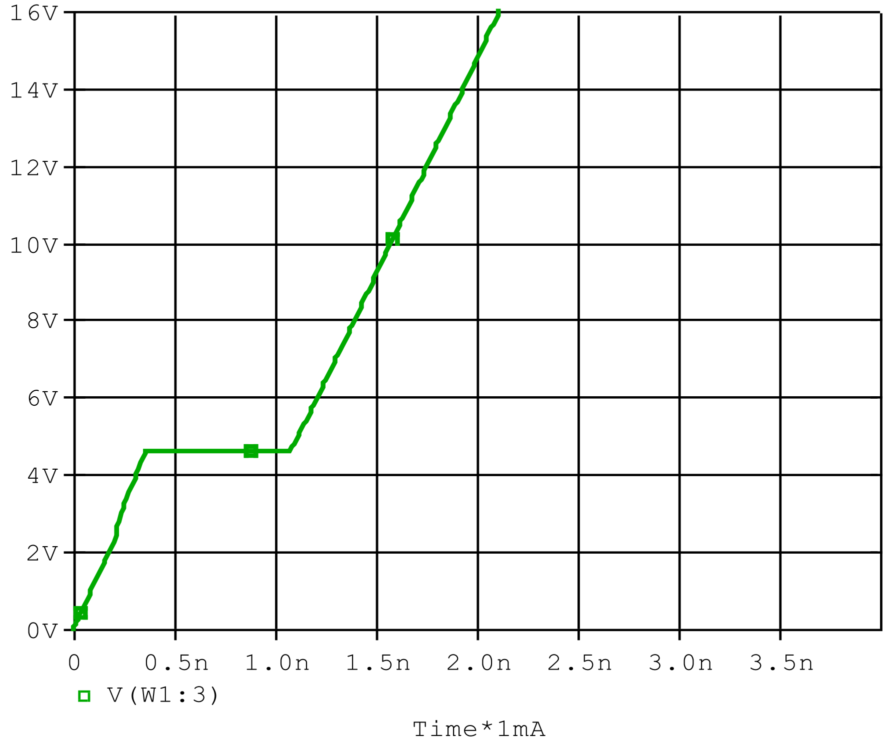


Simulation Result

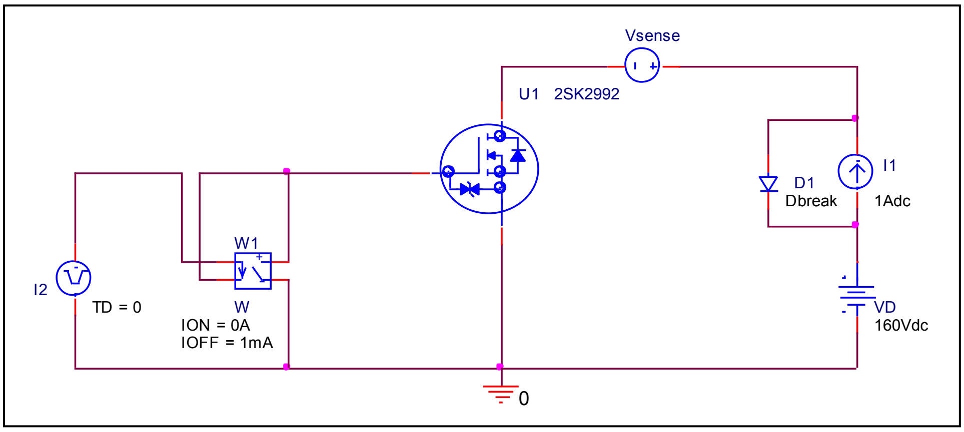
I_D=0.5A, V_{GS}=10V	Measurement		Simulation		Error (%)
R_{DS} (on)	2.2	Ω	2.2	Ω	0.000

Gate Charge Characteristic

Circuit Simulation result



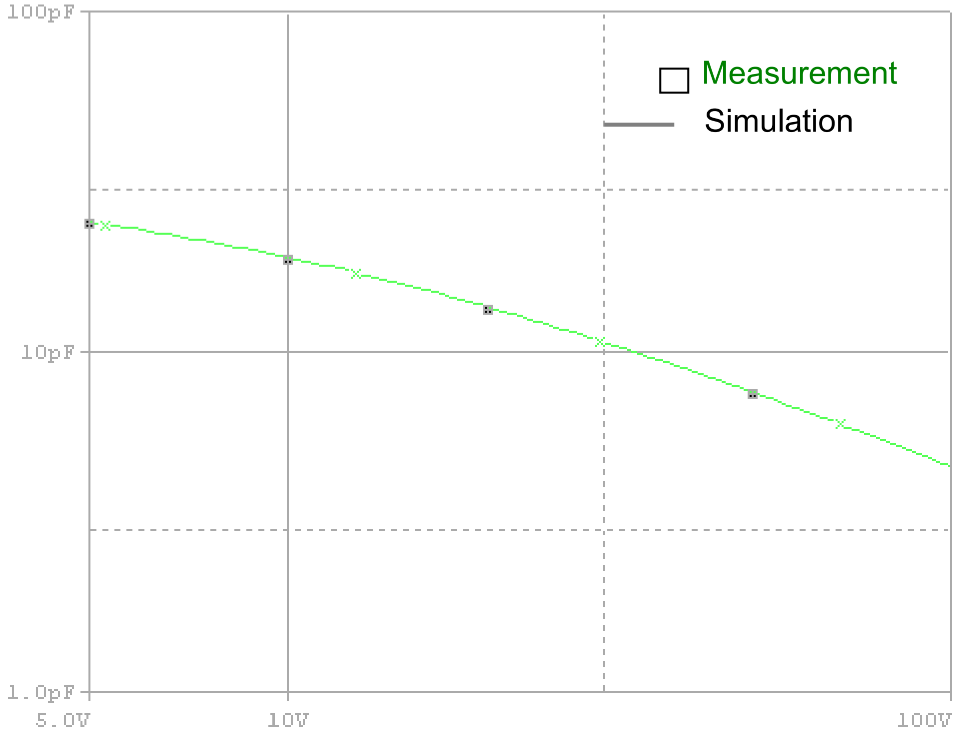
Evaluation circuit



Simulation Result

V_{DD}=160V, I_D=1A	Measurement		Simulation		Error (%)
Qgs	0.3600	nC	0.3590	nC	-0.2778
Qgd	1.0800	nC	1.0850	nC	0.4630

Capacitance Characteristic

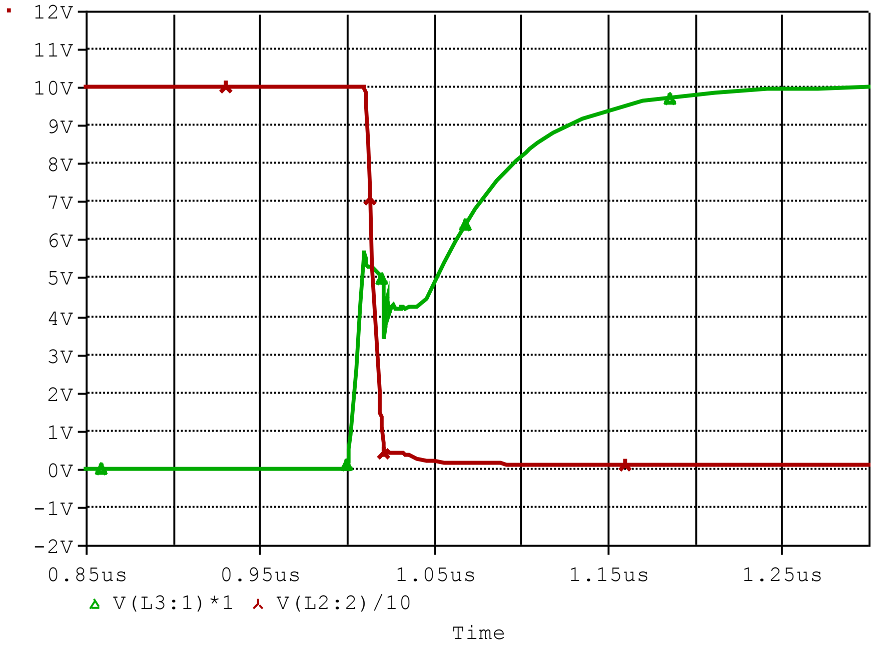


Simulation Result

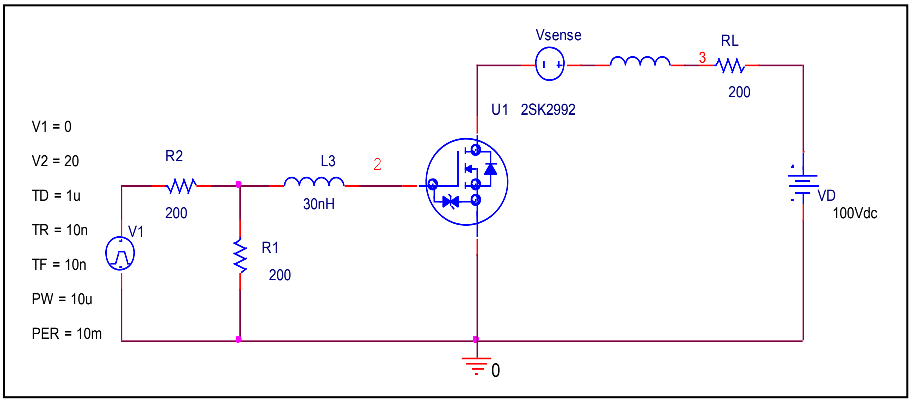
V_{DS}(V)	Cbd(pF)		Error(%)
	Measurement	**Simulation**	
5	**24.000**	**24.119**	**0.496**
10	**19.000**	**18.911**	**-0.468**
20	**13.500**	**13.514**	**0.104**
50	**7.600**	**7.615**	**0.197**

Switching Time Characteristic

Circuit Simulation result



Evaluation circuit

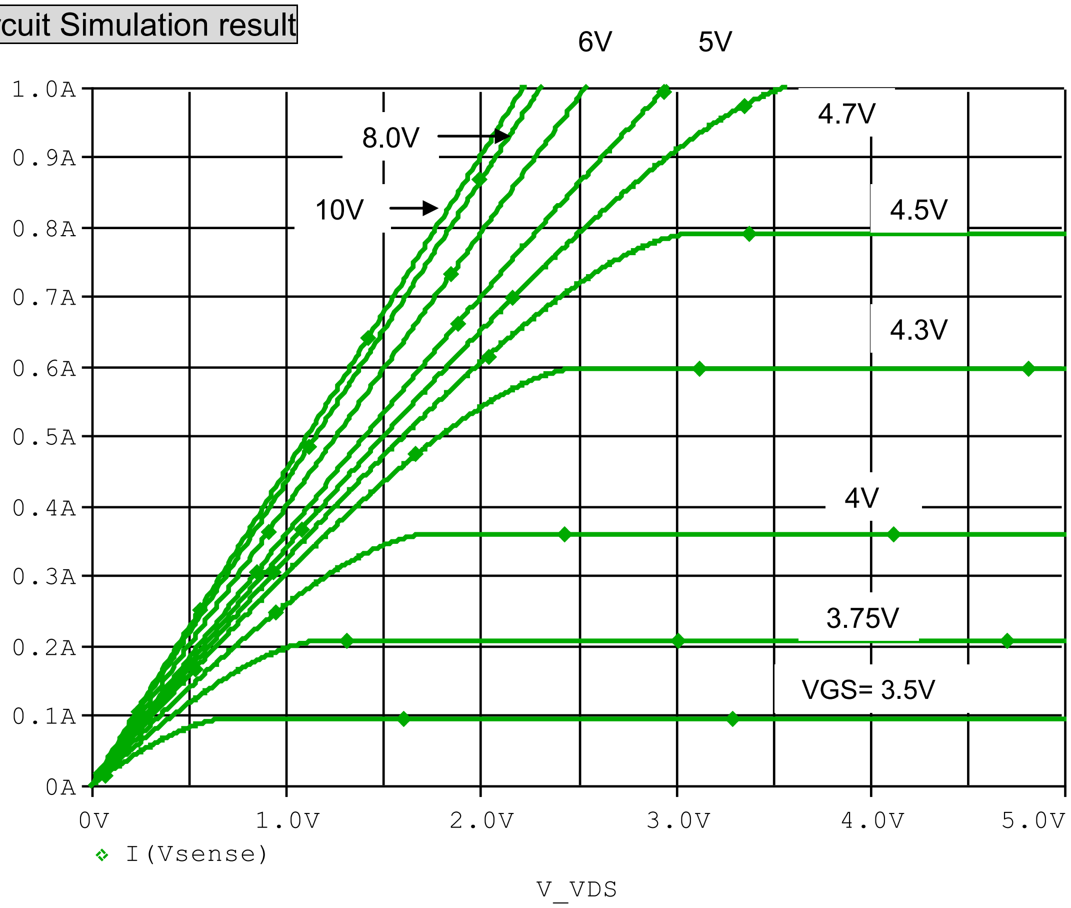


Simulation Result

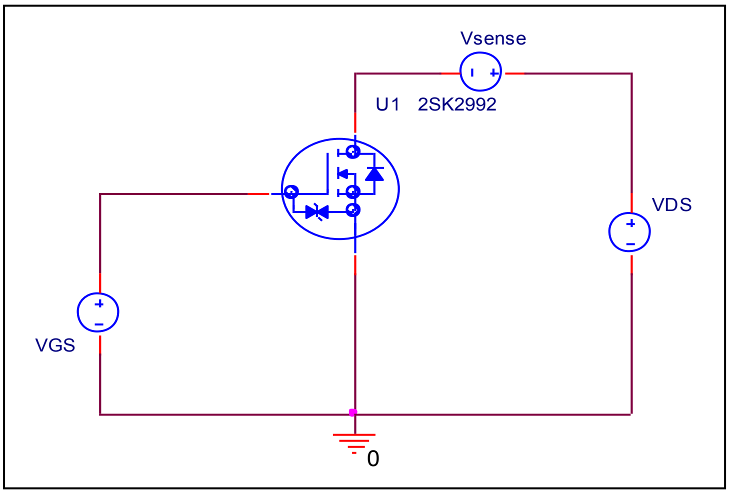
I_D=0.5A, V_{DD}= 100V, V_{GS}=0/10V	Measurement		Simulation		Error(%)
Td(on)	17.000	ns	17.050	ns	0.2941

Output Characteristic

Circuit Simulation result

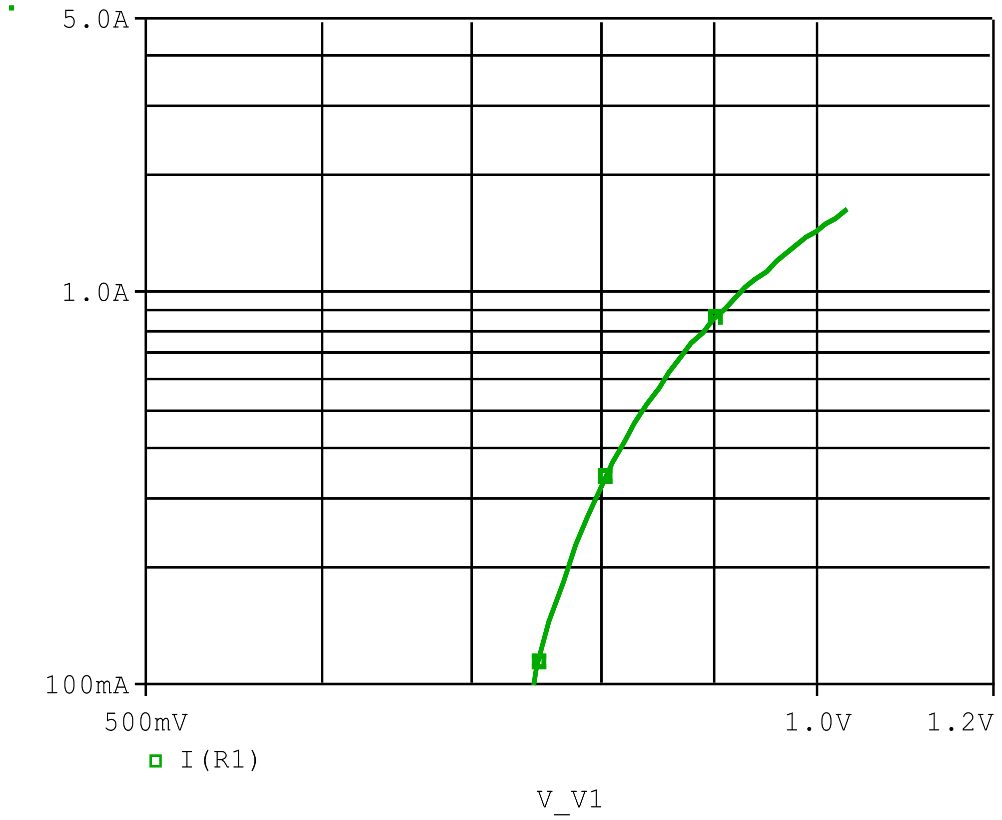


Evaluation circuit

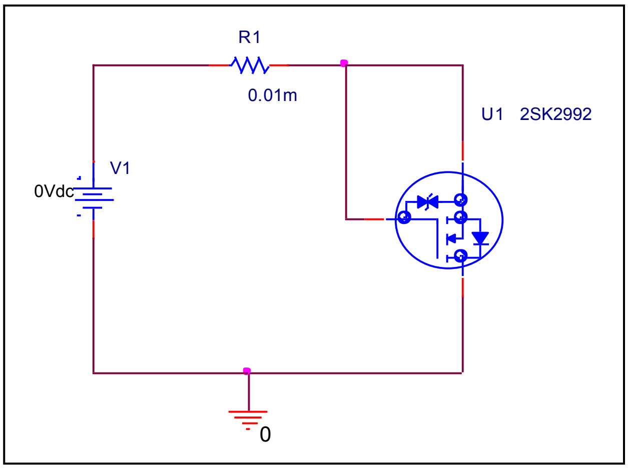


BODY DIODE SPICE MODEL
Forward Current Characteristic

Circuit Simulation Result

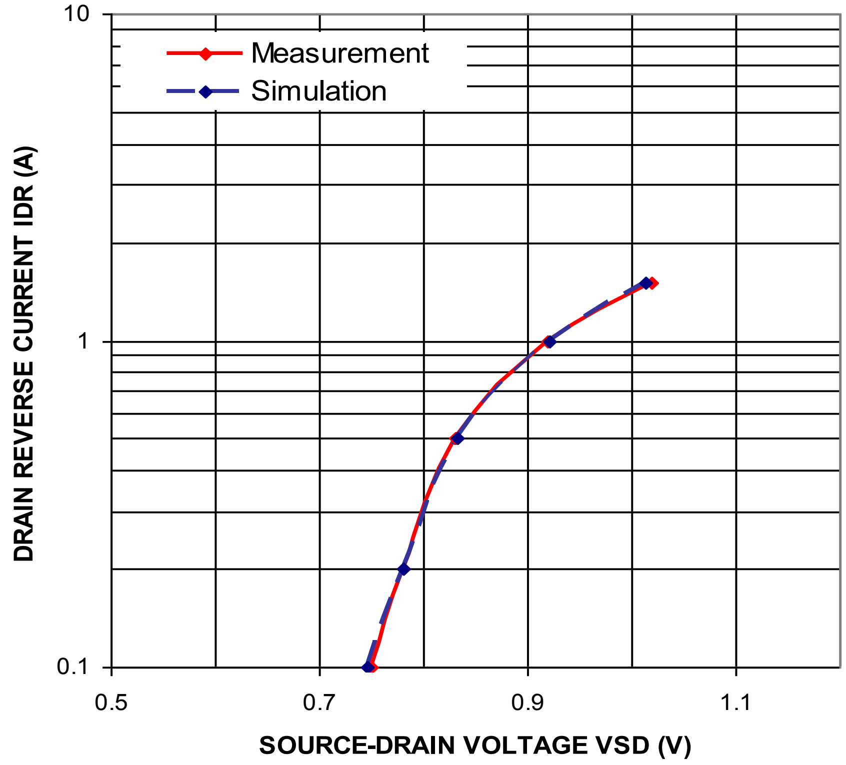


Evaluation Circuit



Comparison Graph

Circuit Simulation Result

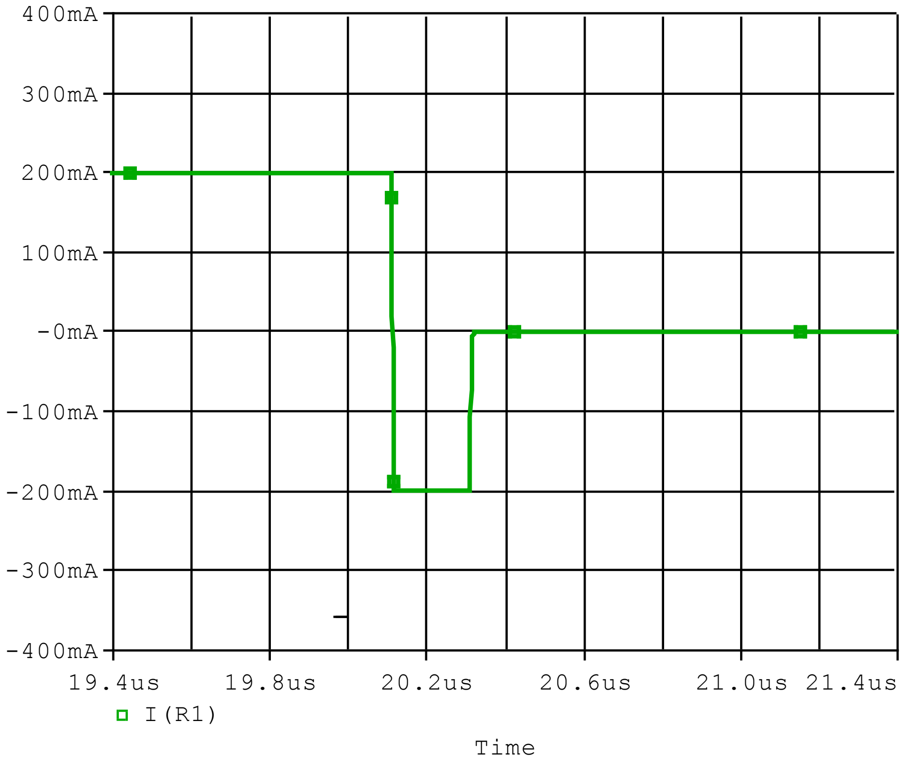


Simulation Result

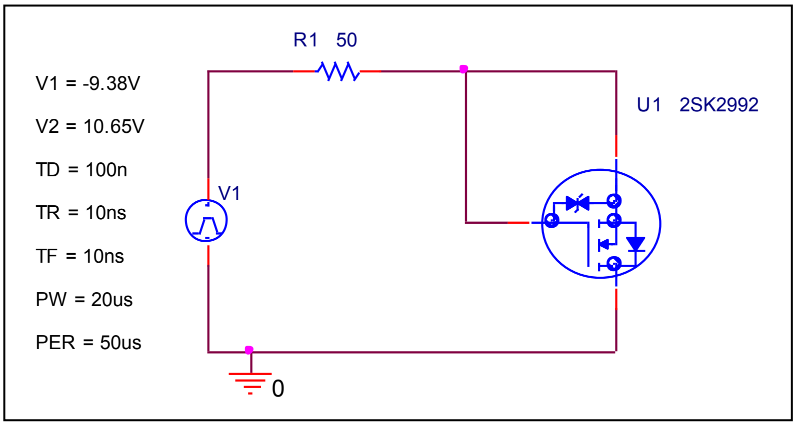
IDR(A)	VSD(V)		%Error
	Measurement	Simulation	
0.1	0.7500	0.7469	-0.4133
0.2	0.7800	0.7800	0.0000
0.5	0.8300	0.8320	0.2410
1	0.9200	0.9210	0.1087
1.5	1.0200	1.0132	-0.6667

Reverse Recovery Characteristic (Body Diode)

Circuit Simulation Result



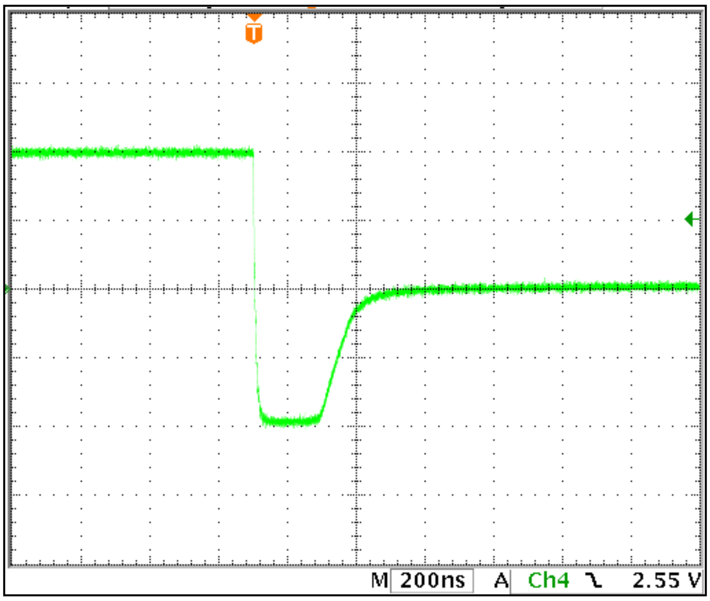
Evaluation Circuit



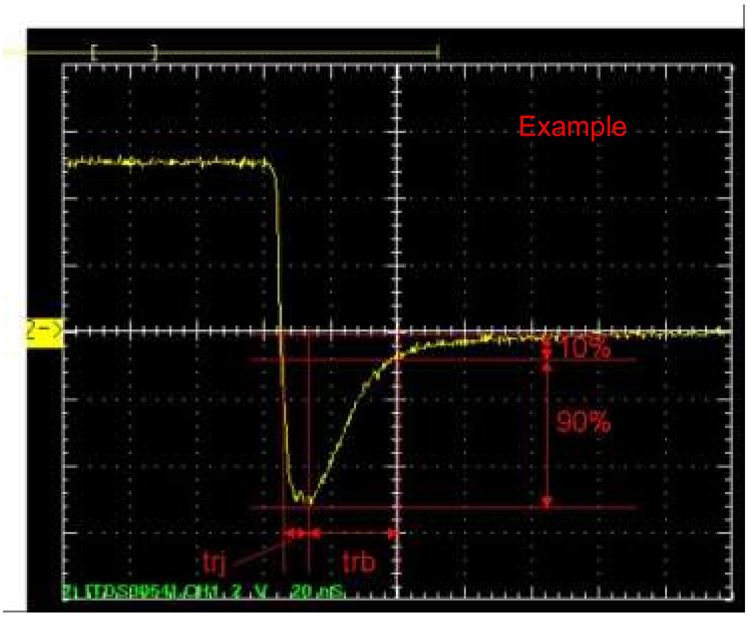
Compare Measurement vs. Simulation

	Measurement		Simulation		Error (%)
trj	196.000	ns	196.100	ns	0.051

Reverse Recovery Characteristic (Body Diode) Reference



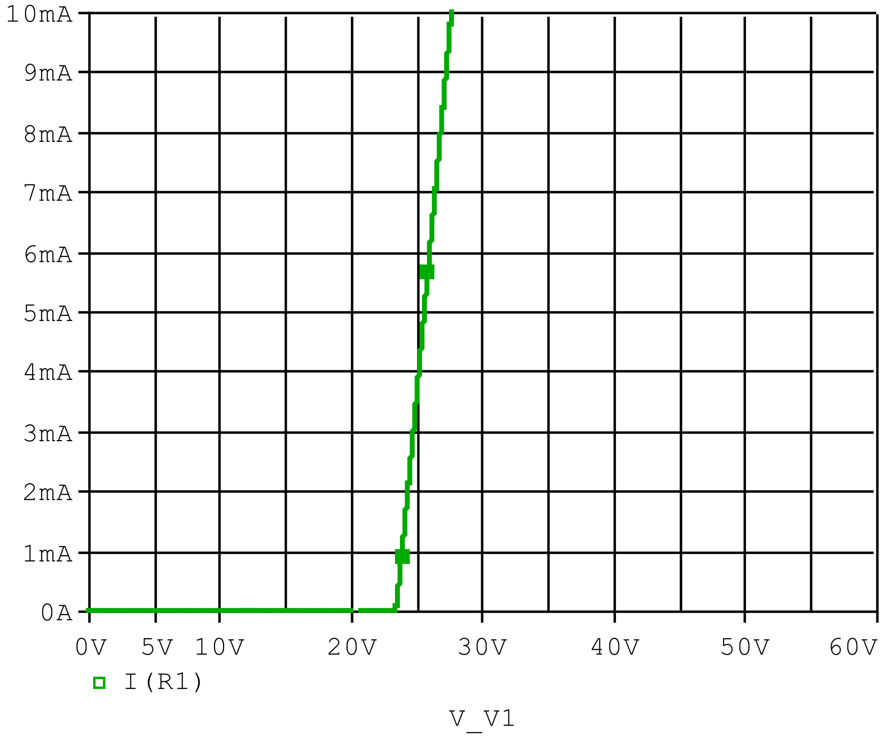
Trj= (196ns)
Trb= (108ns)
Conditions:Ifwd=0.2,Irev=0.2(A),Rl=50



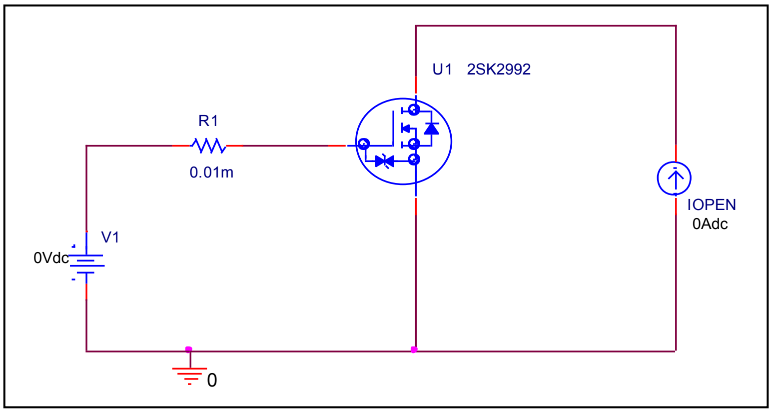
Relation between trj and trb

Zener Voltage Characteristic

Circuit Simulation Result



Evaluation Circuit



Zener Voltage Characteristic **Reference**